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(54) **REFERENCE GENERATOR**

(75) Inventors: **Jishnu Bhattacharjee**, San Jose, CA (US); **Debanjan Mukherjee**, San Jose, CA (US); **Fabian Giroud**, San Jose, CA (US)

(73) Assignee: **Scintera Networks, Inc.**, San Jose, CA (US)

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(58) **Field of Search** 341/144, 155, 341/135, 154; 326/30, 31, 33, 34; 327/108, 327/109, 530, 538

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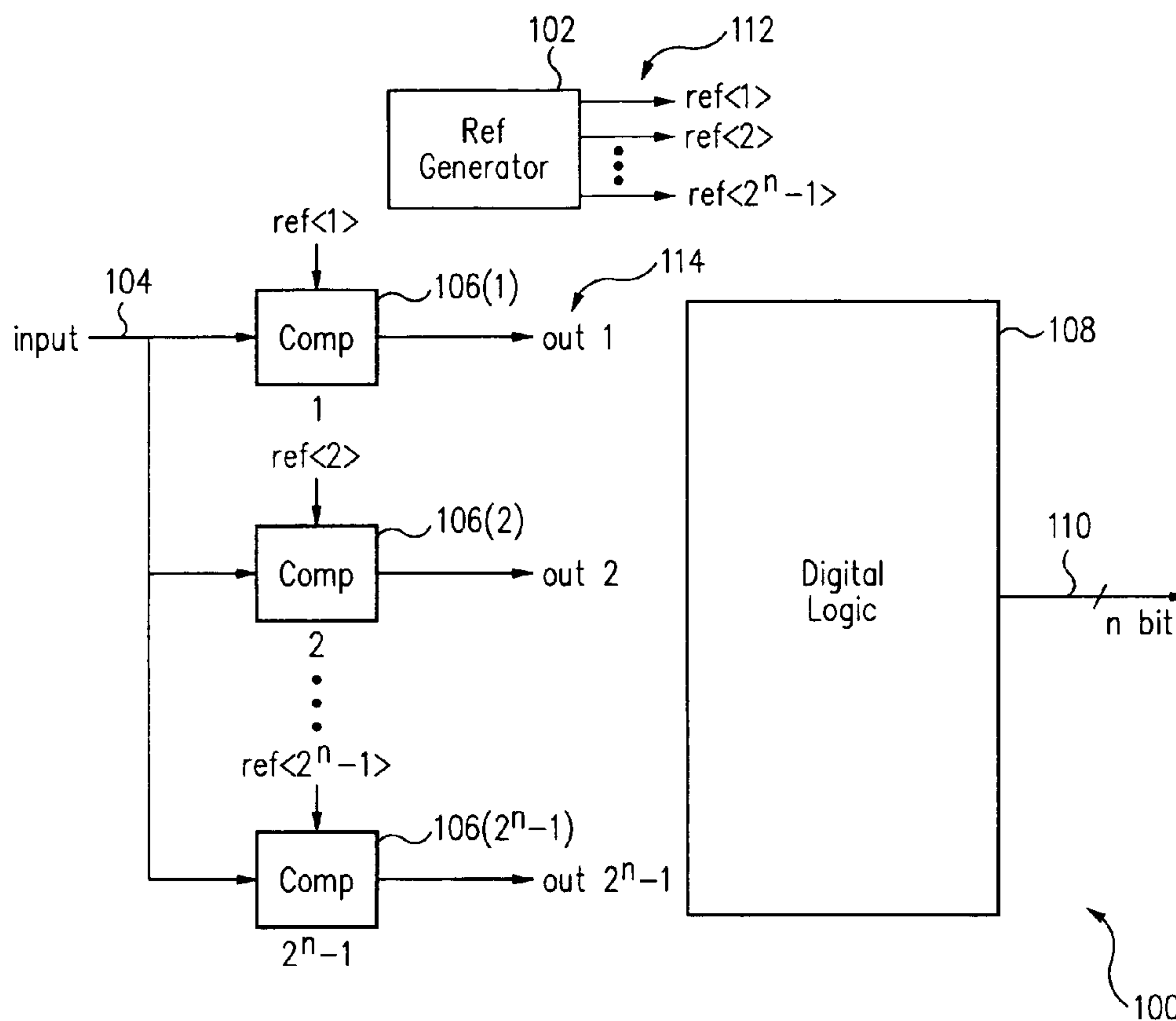
Primary Examiner—Brian Young

(74) *Attorney, Agent, or Firm*—MacPherson Kwok Chen & Heid LLP; Greg J. Michelson

(57) **ABSTRACT**

Systems and methods are disclosed herein to provide reference generators. For example, in accordance with an embodiment of the present invention, a reference generator is provided for an electrical device, such as for example for an analog-to-digital converter. The reference generator may provide one or more reference signals having a common mode voltage that can track or be varied based on a common mode voltage of an input signal. Alternatively or in addition, the reference generator may provide reference signals for single-ended applications.

19 Claims, 3 Drawing Sheets



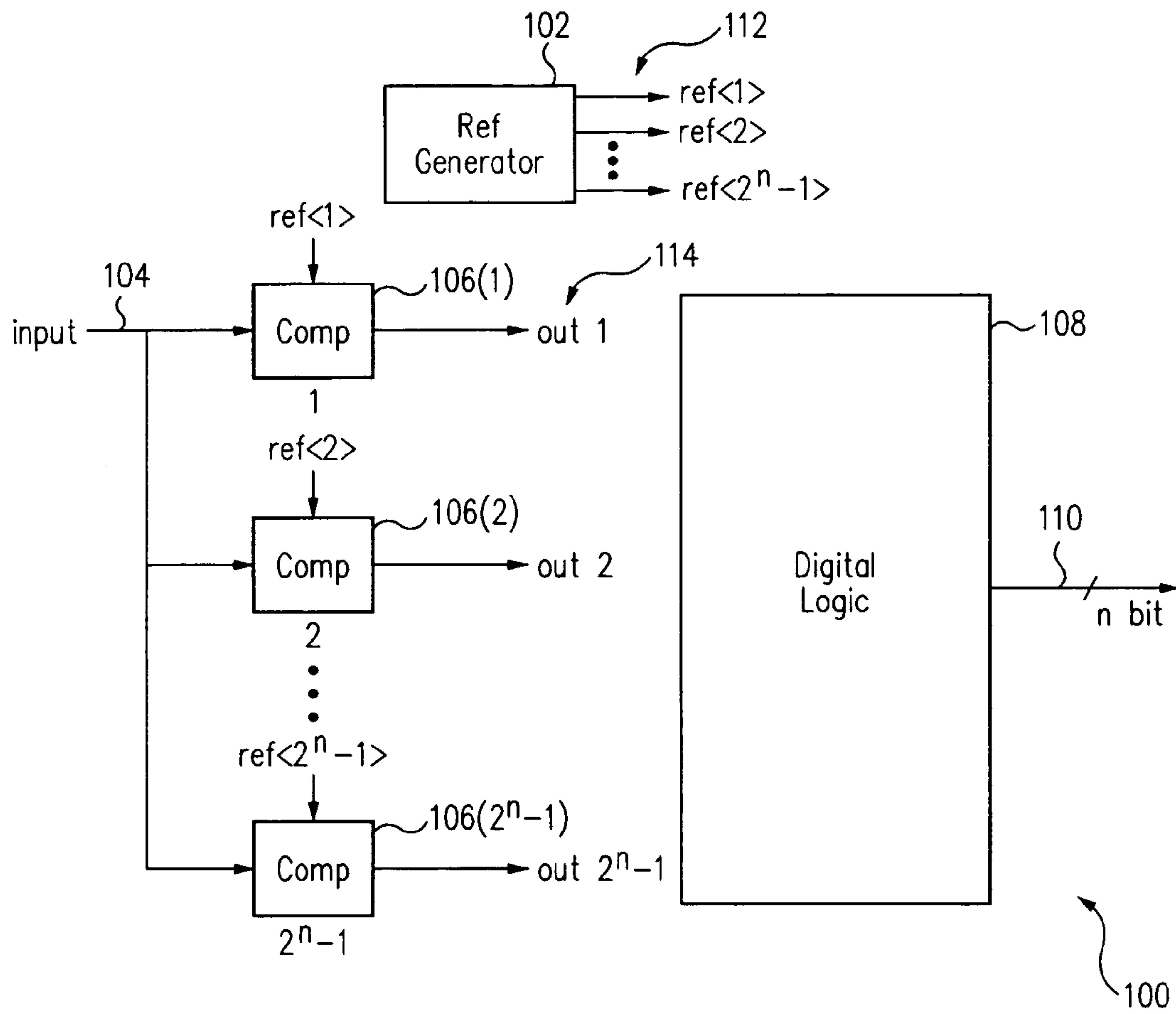


FIG. 1

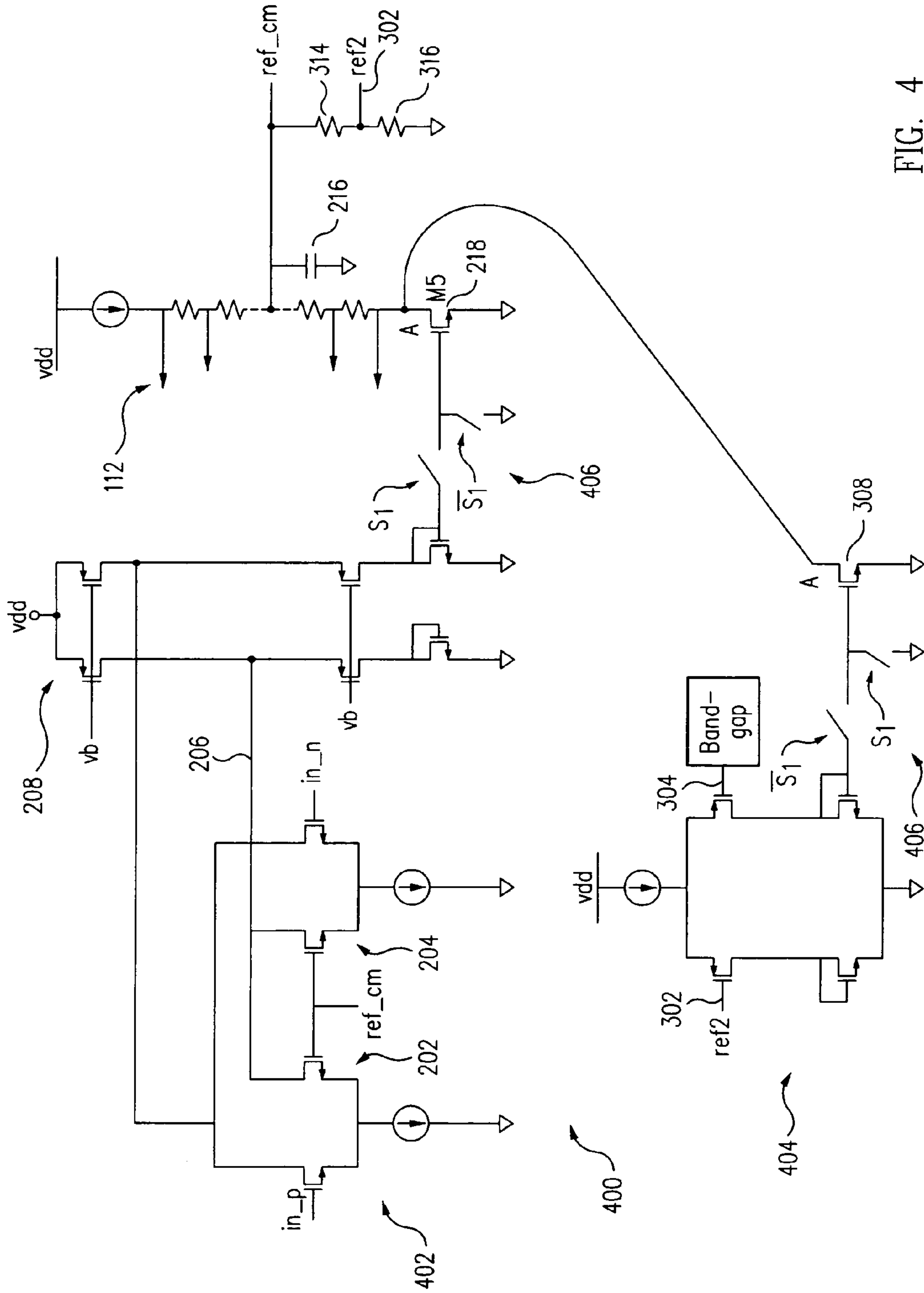


FIG. 4

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REFERENCE GENERATOR

TECHNICAL FIELD

The present invention relates generally to electrical circuits and, more particularly, to reference generators.

BACKGROUND

Reference generators are employed in a variety of circuit applications where one or more reference signals are desired. For example, a reference generator may be employed to provide a reference signal for an analog-to-digital converter (ADC).

One drawback of a conventional reference generator is that the generated reference signal does not adjust according to an input signal (e.g., to an ADC). As an example, a common mode voltage of the generated reference signal may be fixed and, therefore, would be unable to adjust if a common voltage of the input signal were to vary. Furthermore, the conventional reference generator may lack the flexibility to be incorporated into a variety of applications having various input signals and reference voltage requirements. As a result, there is a need for improved reference generator techniques.

SUMMARY

Systems and methods are disclosed herein to provide reference generators. For example, in accordance with an embodiment of the present invention, a reference generator is provided for an electrical device, such as for example for an analog-to-digital converter. The reference generator may provide one or more reference signals having a common mode voltage that can be varied based on a common mode voltage of an input signal. Furthermore, the reference generator may provide reference signals for single-ended or differential signal applications.

More specifically, in accordance with one embodiment of the present invention, an integrated circuit includes a first circuit adapted to receive one or more reference signals; and a reference generator adapted to provide the one or more reference signals, wherein the reference generator includes differential amplifiers adapted to compare a common mode voltage of a differential input signal to a common mode voltage of the one or more reference signals and provide a first signal based on the comparison; and a reference ladder adapted to receive the first signal and provide the one or more reference signals, wherein the first signal controls the common mode voltage of the one or more reference signals.

In accordance with another embodiment of the present invention, a reference generator includes a reference ladder circuit adapted to provide at least one single-ended reference signal or at least one differential reference signal; a first circuit adapted to compare a first reference signal to one of the single-ended reference signals and, based on the comparison, provide a first signal to the reference ladder circuit to control a voltage level of the single-ended reference signals; and a second circuit adapted to compare a common mode voltage level of the differential reference signal to a common mode voltage level of a differential input signal and, based on the comparison, provide a second signal to the reference ladder circuit to control the common mode voltage level of the differential reference signals.

In accordance with another embodiment of the present invention, a method of providing one or more reference signals includes sensing a common mode voltage of an input

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signal; comparing the common mode voltage of the input signal to a common mode voltage of the reference signals; and modifying the common mode voltage of the reference signals to track the common mode voltage of the input signal.

The scope of the invention is defined by the claims, which are incorporated into this section by reference. A more complete understanding of embodiments of the present invention will be afforded to those skilled in the art, as well as a realization of additional advantages thereof, by a consideration of the following detailed description of one or more embodiments. Reference will be made to the appended sheets of drawings that will first be described briefly.

BRIEF DESCRIPTION OF THE DRAWINGS

FIG. 1 shows a block diagram illustrating an exemplary application for a reference generator in accordance with an embodiment of the present invention.

FIG. 2 shows a circuit diagram for the reference generator of FIG. 1 in accordance with an embodiment of the present invention.

FIG. 3 shows a circuit diagram for the reference generator of FIG. 1 in accordance with an embodiment of the present invention.

FIG. 4 shows a circuit diagram for the reference generator of FIG. 1 in accordance with an embodiment of the present invention.

Embodiments of the present invention and their advantages are best understood by referring to the detailed description that follows. It should be appreciated that like reference numerals are used to identify like elements illustrated in one or more of the figures.

DETAILED DESCRIPTION

FIG. 1 shows a circuit 100, which is a circuit block diagram illustrating an exemplary application for a reference generator 102 in accordance with an embodiment of the present invention. For example, circuit 100 may represent a flash analog-to-digital converter (ADC) that receives an input signal 104 (e.g., an analog signal) and provides an output signal 110 (e.g., an n-bit digital signal).

Comparators 106 compare input signal 104 to reference signals 112 (e.g., labeled ref<1> through ref<2ⁿ-1>), provided by reference generator 102, and provide corresponding output signals 114 (e.g., labeled out 1 through out 2ⁿ-1) to a logic circuit 108 (e.g., a digital logic circuit) that provides output signal 110. Reference signals 112 from reference generator 102 are provided to corresponding ones of comparators 106 (which are separately referenced as comparator 106(1) through comparator 106(2ⁿ-1)) as illustrated in FIG. 1 (e.g., ref<1> to comparator 106(1), ref<2> to comparator 106(2), . . . , and ref<2ⁿ-1> to comparator 106(2ⁿ-1)).

As indicated above, circuit 100 may represent an exemplary application for reference generator 102. The flash ADC portion of circuit 100 (i.e., comparators 106 and logic circuit 108) may represent and operate as a conventional flash ADC (e.g., a word at a time architecture) as is known in the art. Reference generator 102, in accordance with an embodiment of the present invention, may be implemented to provide differential operation, single-ended operation, or selectively both, depending upon the requirements or desired application.

For example, in differential operation, reference generator 102 adjusts a common-mode value of reference signals 112

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(e.g., the ADC reference voltage) to track a common-mode value of input signal **104** (e.g., a differential input). In single-ended operation, reference generator **102** may set and provide one or more of reference signals **112** (e.g., the ADC reference voltage) to a scaled version of a bandgap voltage. Furthermore, as an example, the differential or single-ended operation may include dominant-pole compensation to provide unconditional stability.

As an example, FIG. 2 shows a circuit **200**, which is an exemplary circuit implementation for differential operation for reference generator **102** of FIG. 1 in accordance with an embodiment of the present invention. Circuit **200** receives input signal **104** (i.e., a differential input signal whose signals are labeled in_p and in_n) via differential amplifiers **202** and **204**, respectively, which also receive a reference signal **214** (labeled ref_cm). Reference signal **214**, generated by circuit **200**, provides a common-mode voltage of reference signals **112**.

Differential amplifiers **202** and **204** sense the difference between the common-mode voltage of input signal **104** and the common-mode voltage of reference signals **112** (as provided by reference signal **214**) and amplifies the difference to provide a difference signal **206**. Difference signal **206** is fed back to a transistor **218** (e.g., providing a variable resistance) via a circuit **208** (which also receives a bias voltage (labeled Vb) and a supply voltage (labeled Vdd)). In general, as a resistance value of transistor **218** increases (under control of difference signal **206**), a voltage level of reference signal **214** (i.e., a common-mode voltage level of reference signals **112**) increases also.

A reference ladder **210** in circuit **200** includes a current source **212**, transistor **218**, and a plurality of resistors **220**. Reference ladder **210** provides reference signals **112** and reference signal **214**. Reference signals **112** (which for this example are provided as differential signals, e.g., ref<1>, ref<2>, . . . , ref<2ⁿ-1>) are taken from corresponding points from among resistors **220** (e.g., as illustrated by the double-headed arrows designating exemplary corresponding points among resistors **220**).

A current I, flowing through reference ladder **210**, controls a resolution (e.g., a least significant bit (LSB)) of reference ladder **210** (e.g., an ADC reference ladder). For example, a step size (or LSB) may be determined by a value of the current I times a value of a resistance (R) of one of resistors **220** (or I times R, where each of resistors **220** has the same resistor value (R)). The step size may be determined independent of a resistance provided by transistor **218**.

A common-mode node **222** of reference ladder **210**, which provides reference signal **214** (labeled ref_cm), may also include a capacitor **216** to function as a dominant pole for a first order negative feedback loop (e.g., for providing reference signal **214**). The dominant pole may also improve power supply rejection for reference signal **214** and provide voltage stability (e.g., to filter out power supply voltage fluctuations).

In general, circuit **200** illustrates a reference ladder architecture for providing reference voltages **112** and common-mode tracking of input signal **104** having differential inputs. Circuit **200** may provide various functions. For example, circuit **200** senses a common mode voltage of a differential input signal (e.g., input signal **104**) to be measured. Circuit **200** also compares the common mode voltage of the differential input signal with a common mode voltage of a reference signal (e.g., reference signal **214**). Additionally, circuit **200** changes the common mode voltage of the reference signal in the appropriate direction to track the

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common mode voltage of the differential input signal (e.g., to provide negative feedback).

As another example, FIG. 3 shows a circuit **300**, which is an exemplary implementation for single-ended operation for reference generator **102** of FIG. 1 in accordance with an embodiment of the present invention. Circuit **300** compares a reference voltage **302** with a reference voltage **304**, with a result of the comparison provided to a transistor **308** (e.g., to vary its resistance).

Transistor **308** is coupled to a number of resistors **312** and a current source **310**, with circuit **300** providing one or more of reference signals **112** (e.g., 2ⁿ-1 single-ended reference signals). A reference signal **306**, which may be selected from any one of reference signals **112** in FIG. 3, may be divided down via resistors **314** and **316** to an appropriate voltage level to generate reference signal **302**, which is compared to reference signal **304**. In general, reference signal **306** may be reduced to generate reference signal **302** to compare to a voltage level of reference signal **304**, such that reference signal **304** is approximately equal to a voltage level of reference signal **306** times a resistance (R2) of resistor **316** divided by the sum of the resistance (R2) of resistor **316** and a resistance (R1) of resistor **314**. It should be noted that in general the resistance provided by resistors **314** and **316** will be much greater than the parallel current path provided through transistor **308** and a certain number of resistors **312**.

Alternatively, reference signal **306** may be compared directly to reference signal **304** (i.e., feedback reference signal **306** as reference signal **302** for comparison to reference signal **304**) if a voltage level of reference signal **306** is suitable for comparison relative to a voltage level of reference signal **304**. As an example, reference signal **304** may be generated by bandgap reference voltage techniques to provide a stable reference voltage, such as for example as described in U.S. patent application Ser. No. 10/724,440, filed Nov. 26, 2003 and entitled "Trimmable Bandgap Voltage Reference."

As discussed herein, reference generator **102** of FIG. 1 may be implemented for differential operation (e.g., as discussed in reference to FIG. 2) or for single-ended operation (e.g., as discussed in reference to FIG. 3). Alternatively, reference generator **102** may be implemented to selectively provide differential operation or single-ended operation.

For example, FIG. 4 shows a circuit **400**, which is an exemplary circuit implementation for reference generator **102** of FIG. 1 in accordance with an embodiment of the present invention. Circuit **400** includes a circuit **402** and a circuit **404**, with circuit **402** providing differential operation as described similarly for circuit **200** (FIG. 2) and circuit **404** providing single-ended operation as described similarly for circuit **300** (FIG. 3). Switches **406** are provided to allow the selection of differential operation (circuit **402**) or single-ended operation (circuit **404**). For example, when a signal S1 is asserted, circuit **402** is selected and circuit **404** is deselected, while when the signal S1 is deasserted, circuit **402** is deselected and circuit **404** is selected.

It should also be understood that reference generator **102** may include a number of circuits **200** and/or circuits **300** to provide the desired number of reference signals. For example, reference generator **102** may include one or more of circuits **200**, **300**, and/or **400** to provide the desired reference signals utilizing the techniques discussed herein.

In accordance with one or more embodiments of the present invention, a reference generator is provided for various circuit applications. For example, the reference generator may be employed to provide reference voltages for an ADC. The reference generator may provide a refer-

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ence common mode for differential operation that tracks a common mode of an input signal to the ADC. The reference generator may alternatively or also provide one or more reference signals for single-ended operation. It should also be understood that the circuit implementations are exemplary and are not limiting. For example, the choice of transistors (e.g., NMOS or PMOS) will depend upon the application (e.g., the signal levels to be tracked).

Embodiments described above illustrate but do not limit the invention. It should also be understood that numerous modifications and variations are possible in accordance with the principles of the present invention. Accordingly, the scope of the invention is defined only by the following claims.

We claim:

1. An integrated circuit comprising:
 - a first circuit adapted to receive one or more reference signals; and
 - a reference generator adapted to provide the one or more reference signals, wherein the reference generator comprises:
 - differential amplifiers adapted to compare a common mode voltage of a differential input signal to a common mode voltage of the one or more reference signals and provide a first signal based on the comparison; and
 - a reference ladder adapted to receive the first signal and provide the one or more reference signals, wherein the first signal controls the common mode voltage of the one or more reference signals.
2. The integrated circuit of claim 1, wherein the reference ladder comprises:
 - a current source;
 - a plurality of resistors, wherein the one or more reference signals are provided from corresponding nodes among the plurality of resistors; and
 - a transistor, wherein the transistor is adapted to receive the first signal which varies a resistance of the transistor to determine the common mode voltage of the one or more reference signals.
3. The integrated circuit of claim 2, wherein each of the resistors has a first resistor value and a resolution of the reference ladder is determined by the first resistor value and a current flowing through the reference ladder.
4. The integrated circuit of claim 1, wherein the common mode voltage of the one or more reference signals tracks the common mode voltage of the differential input signal.
5. The integrated circuit of claim 1, wherein the first circuit is an analog-to-digital converter adapted to receive the differential input signal and provide a digital output signal.
6. The integrated circuit of claim 1, further comprising a capacitor coupled to the reference ladder.
7. The integrated circuit of claim 5, wherein the capacitor provides dominant pole compensation and voltage stability.
8. The integrated circuit of claim 1, wherein the reference generator is further adapted to provide a single-ended reference signal, wherein the reference generator further comprises:
 - a comparison circuit adapted to compare a first reference voltage to the single-ended reference signal and provide a second signal; and
 - a second transistor, coupled to the reference ladder, adapted to receive the second signal and control a voltage level of the single-ended reference signal.

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9. The integrated circuit of claim 8, wherein the first reference signal is a bandgap reference voltage.

10. The integrated circuit of claim 8, further comprising at least one switch, wherein the switch is controlled to determine whether the single-ended reference signal or the one or more reference signals are provided by the reference generator.

11. A reference generator comprising:

- a reference ladder circuit adapted to provide at least one single-ended reference signal or at least one differential reference signal;
- a first circuit adapted to compare a first reference signal to one of the single-ended reference signals and, based on the comparison, provide a first signal to the reference ladder circuit to control a voltage level of the single-ended reference signals; and
- a second circuit adapted to compare a common mode voltage level of the differential reference signal to a common mode voltage level of a differential input signal and, based on the comparison, provide a second signal to the reference ladder circuit to control the common mode voltage level of the differential reference signals.

12. The reference generator of claim 11, wherein the reference ladder circuit comprises;

- a current source;
- a plurality of resistors; and
- at least a first transistor adapted to vary its resistance based on a value of the first signal or the second signal.

13. The reference generator of claim 11, further comprising at least one switch, wherein the at least one switch determines whether the single-ended reference signals or the differential reference signals are provided by the reference generator.

14. The reference generator of claim 11, wherein the second signal controls the common mode voltage level of the differential reference signals to track the common mode voltage level of the differential input signal.

15. The reference generator of claim 11, further comprising a capacitor coupled to the reference ladder circuit.

16. The reference generator of claim 15, wherein the capacitor provides dominant pole compensation and power supply rejection.

17. A method of providing one or more reference signals, the method comprising:

- sensing a common mode voltage of an input signal;
- comparing the common mode voltage of the input signal to a common mode voltage of the reference signals; and
- modifying the common mode voltage of the reference signals to track the common mode voltage of the input signal.

18. The method of claim 17, further comprising providing dominant pole compensation to provide voltage stability for the reference signals.

19. The method of claim 17, further comprising:

- comparing the reference signals to a first reference signal;
- modifying a voltage level of the reference signals based on the comparing; and
- providing the reference signals as single-ended signals or as differential signals.